

Search Notes

Application/Control No.

10/715,045

Examiner

Yuwen Pan

Applicant(s)/Patent under
Reexamination

SENDYK ET AL.

Art Unit

2618

SEARCHED

Class	Subclass	Date	Examiner
455	101,105,1 03,114.2	12/6/2006	YP
	126		
375	141		
	146-148		
370	334,339		
	209,441		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	12/6/2006	YP